International Workshop on

Software Engineering and Knowledge Management (SEKM 2018)

July 16th to 20th
in Lisbon, Portugal
(Associated with
The 18th IEEE International Conference on Software Quality, Reliability & Security (QRS 2018))

Call for Papers

The SEKM 2018 workshop aims at bringing together experts in software engineering and knowledge management to discuss on relevant results in either software engineering or knowledge management or both. Special emphasis will be put on the transference of methods between both domains.

The topics of interest include (but not limited to):

- Software Engineering Practice
- Web Engineering
- Software Maintenance and Testing
- Formal Methods
- Domain Engineering
- Software Product Line
- Ontology and methodology
- Big Data
- Web-based Education Systems and Learning Applications
- Software Engineering Decision Making
- Search Engines and Information Retrieval
- Requirements engineering
- Cloud Computing
- Knowledge representation and reasoning
- Formal analysis of knowledge and Logics of knowledge
- Knowledge in complex systems and multi-agent systems
- Knowledge extraction and Knowledge integration
- Knowledge-based software engineering
- Knowledge-based and expert system
- Complex system modeling and complexity
- Decision analysis and decision support systems
- Knowledge discovery, data mining, text mining, recommendation system
- Knowledge management strategies and practices
- Web-Based Knowledge Management
Honored General Chairs

- Kokichi Futatsugi, Japan Advanced Institute of Science and Technology, Japan
- Yoshiteru Nakamori, Japan Advanced Institute of Science and Technology, Japan

Program Chairs

- Jing Tian, Wuhan University of Technology, China (jtian@whut.edu.cn)
- Jianwen Xiang, Wuhan University of Technology, China (jwxiang@whut.edu.cn)

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- Min Zhang, East China Normal University, China
- Dongdong Zhao, Wuhan University of Technology, China
- Zheng Zheng, Beihang University, China